

**描述 / Descriptions**

SOP-8 塑封封装互补增强模式 MOS 场效应管。

Complementary Enhancement MOSFET in a SOP-8 Plastic Package.

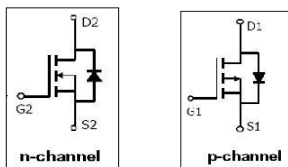
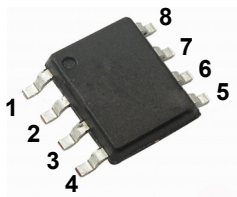
**特征 / Features**

N-channel	P-channel
$V_{DS}(V)=30V$	$V_{DS}(V)=-30V$
$I_D=6.9A$	$I_D=-6A$
$R_{DS(ON)}<28m\ \Omega\ (V_{GS}=10V)$	$R_{DS(ON)}<35m\ \Omega\ (V_{GS}=10V)$
$R_{DS(ON)}<42m\ \Omega\ (V_{GS}=4.5V)$	$R_{DS(ON)}<58m\ \Omega\ (V_{GS}=4.5V)$

**用途 / Applications**

用于高功率 DC/DC 转换和功率开关。适用于作负载开关或脉宽调制应用。

These devices are well suited for high efficiency switching DC/DC converters and switch mode power supplies. This device is suitable for use as a load switch or in PWM applications.

**内部等效电路 / Equivalent Circuit**

**引脚排列 / Pinning**


PIN 1 : S2    PIN 2 : G2    PIN 3 : S1    PIN 4 : G1  
 PIN 5 : D1    PIN 6 : D1    PIN 7 : D2    PIN 8 : D2

**极限参数 / Absolute Maximum Ratings(Ta=25°C)**

参数 Parameter	符号 Symbol	数值 Rating		单位 Unit
		N-channel	P-channel	
Drain-Source Voltage	$V_{DSS}$	±30		V
Gate-Source Voltage	$V_{GSS}$	±20		V
Continuous Drain Current <sup>A</sup>	$I_D (T_A=25^\circ\text{C})$	6.9	-6.0	A
	$I_D (T_A=70^\circ\text{C})$	5.8	-5.0	A
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	±30		A
Power Dissipation	$P_D (T_A=25^\circ\text{C})$	2		W
	$P_D (T_A=70^\circ\text{C})$	1.44		W
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}(t \leq 10\text{s})$	62.5		°C/W
	$R_{\theta JA}$	110		°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	60		°C/W
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to +150		°C

**Notes:**

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ . The value in any a given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

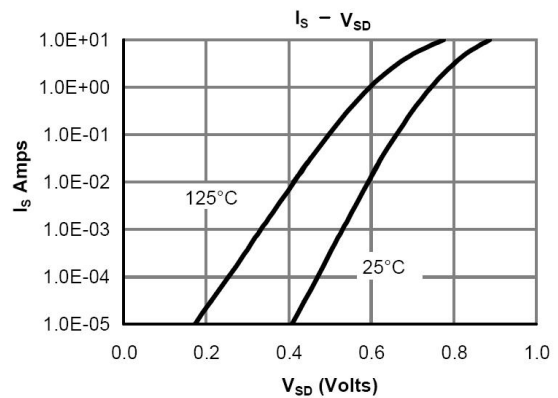
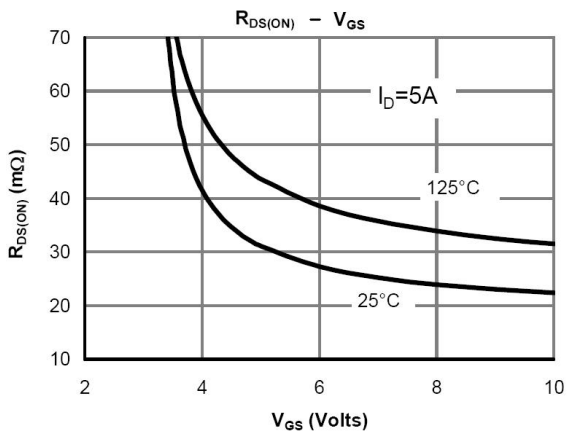
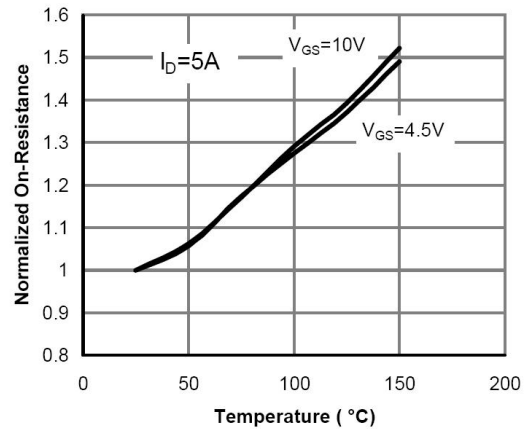
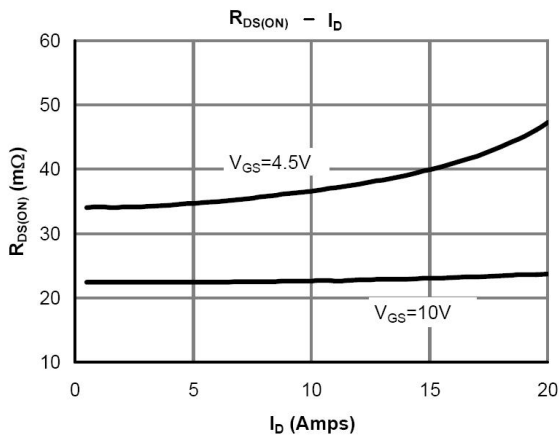
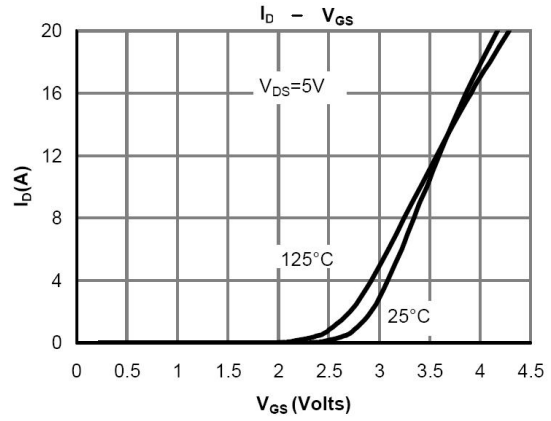
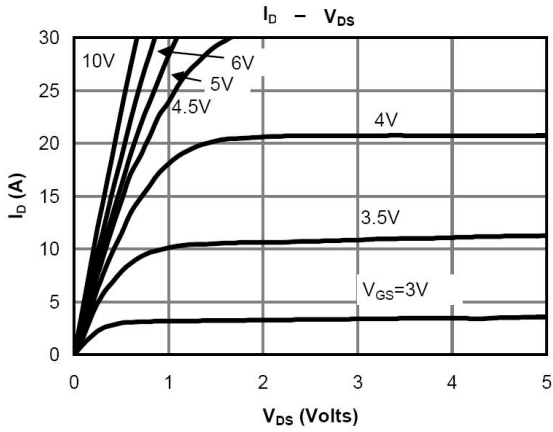
D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

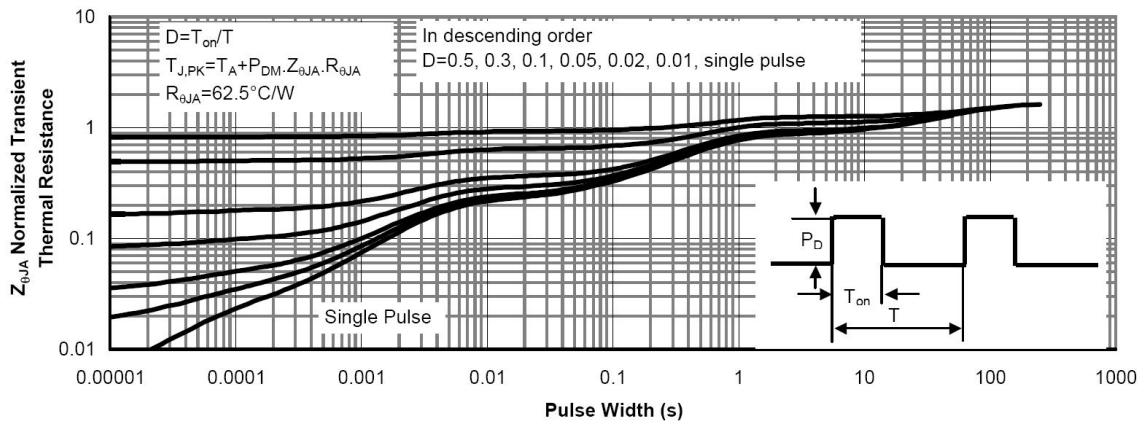
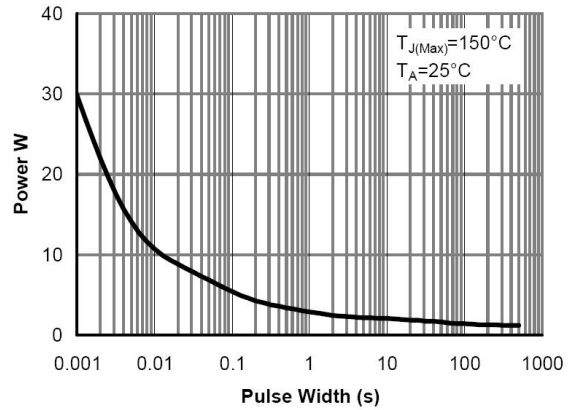
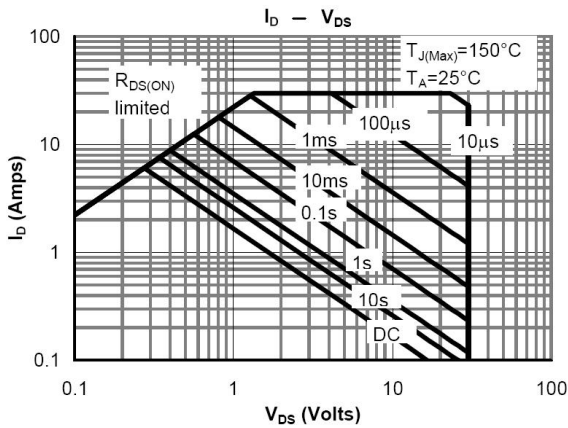
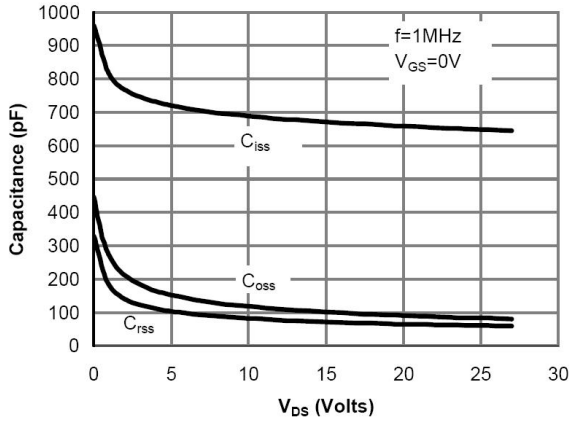
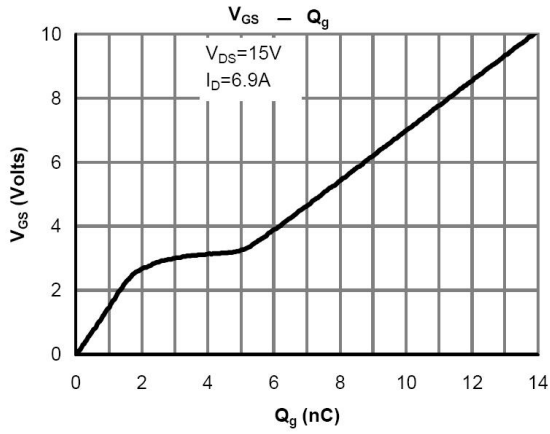
**N-沟道电性能参数/N-CHANNEL Electrical Characteristics(Ta=25°C)**

参数 Parameter	符号 Symbol	测试条件 Test Conditions	最小值 Min	典型值 Typ	最大值 Max	单位 Unit
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS}=0V$ $I_D=250\mu A$	30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=24V$ $V_{GS}=0V$			1.0	$\mu A$
		$V_{DS}=24V$ $V_{GS}=0V$ $T_J=55^\circ C$			5.0	$\mu A$
Gate-Body leakage current	$I_{GSS}$	$V_{GS}=\pm 20V$ $V_{DS}=0V$			100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$ $I_D=250\mu A$	1.0	1.9	3.0	V
On state drain current	$I_{D(on)}$	$V_{DS}=4.5V$ $V_{GS}=5.0V$	20			A
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10V$ $I_D=6.9A$		22.5	28	m $\Omega$
		$V_{GS}=10V$ $I_D=6.9A$ $T_J=125^\circ C$		31.3	38	m $\Omega$
		$V_{GS}=4.5V$ $I_D=5.0A$		34.5	42	m $\Omega$
Forward Transconductance	$g_{FS}$	$V_{DS}=5.0V$ $I_D=6.9A$	10	15.4		S
Diode Forward Voltage	$V_{SD}$	$V_{GS}=0V$ $I_S=1.0A$		0.76	1.0	V
Maximum Body-Diode Continuous Current	$I_S$				3.0	A
Input Capacitance	$C_{iss}$			680		pF
Output Capacitance	$C_{oss}$	$V_{DS}=15V$ $V_{GS}=0V$ $f=1.0MHz$		102		pF
Reverse Transfer Capacitance	$C_{rss}$			77		pF
Gate resistance	$R_g$	$V_{DS}=0V$ $V_{GS}=0V$ $f=1.0MHz$		3.0		$\Omega$
Total Gate Charge(10V)	$Q_g$	$V_{GS}=10V$ $V_{DS}=15V$ $I_D=6.9A$		13.84		nC
Total Gate Charge(4.5V)				6.74		nC
Gate-Source Charge	$Q_{gs}$			1.82		nC
Gate-Drain Charge	$Q_{gd}$			3.2		nC
Turn-On Delay Time	$t_{d(on)}$	$V_{DS}=15V$ $V_{GS}=10V$ $R_L=2.1\Omega$ $R_{GEN}=3\Omega$		4.6		ns
Turn-On Rise Time	$t_r$			4.1		ns
Turn-Off Delay Time	$t_{d(off)}$			20.6		ns
Turn-Off Fall Time	$t_f$			5.2		ns
Body Diode Reverse Recovery Time	$t_{rr}$	$I_F=6.9A$ $dI/dt=100A/\mu s$		16.5		ns
Body Diode Reverse Recovery Charge	$Q_{rr}$	$I_F=6.9A$ $dI/dt=100A/\mu s$		7.8		nC

N-沟道电参数曲线图 / N-CHANNEL Electrical Characteristic Curve



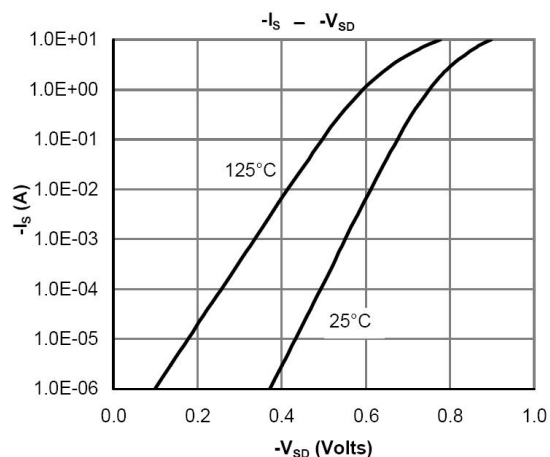
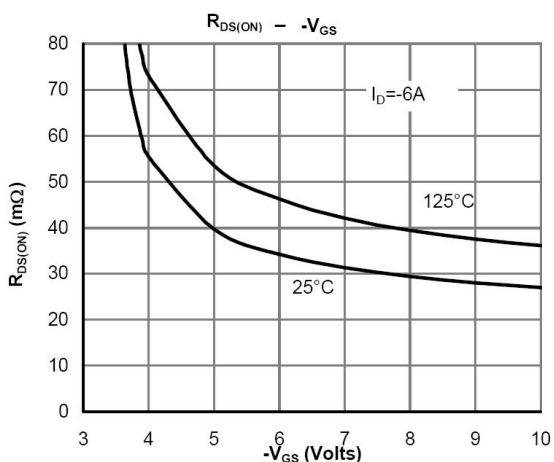
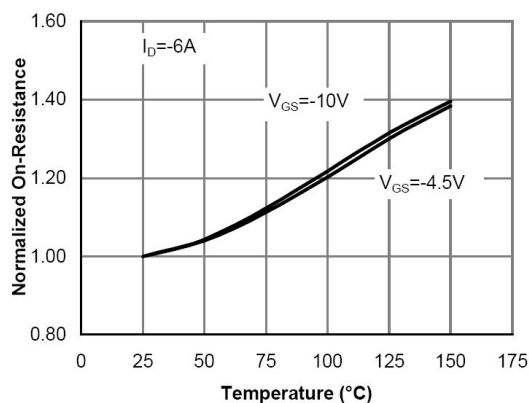
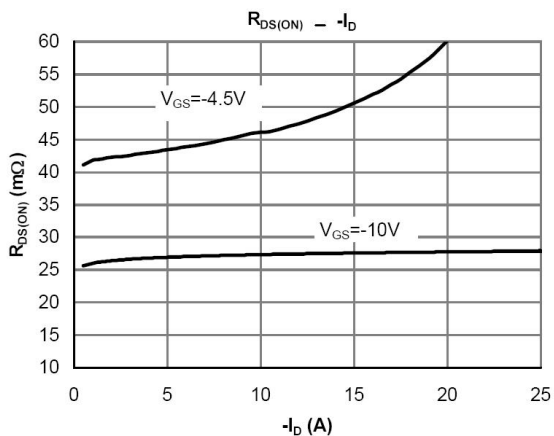
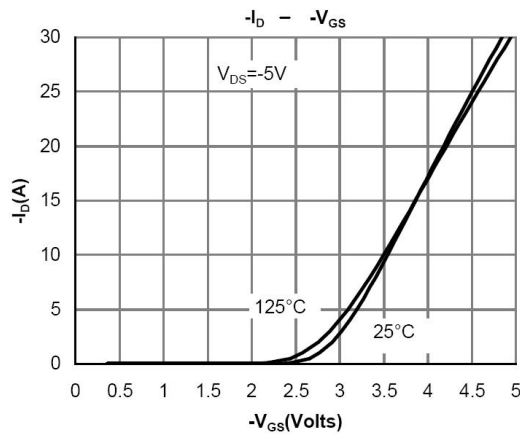
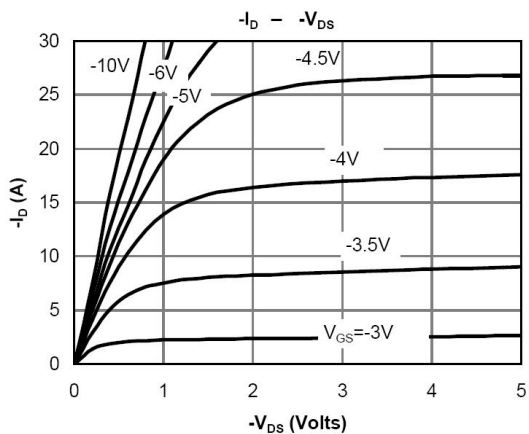
N-沟道电参数曲线图 / N-CHANNEL Electrical Characteristic Curve



**P-沟道电性能参数/P-CHANNEL Electrical Characteristics(Ta=25°C)**

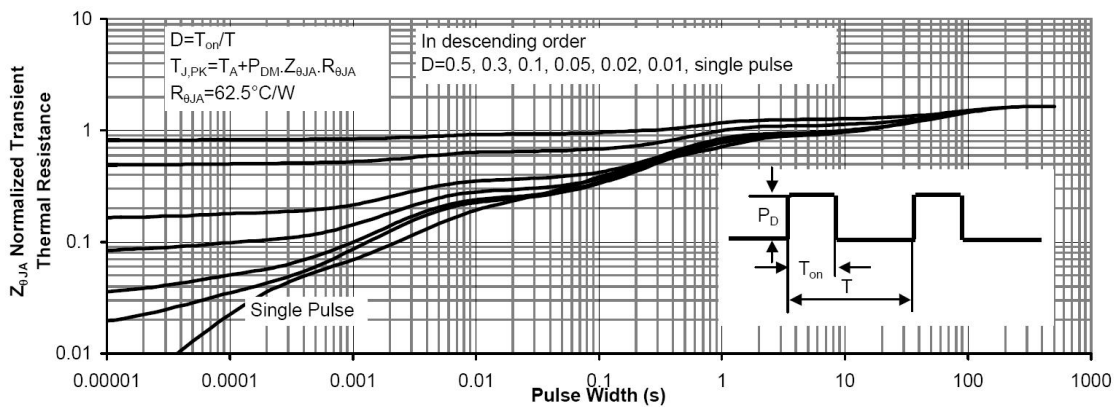
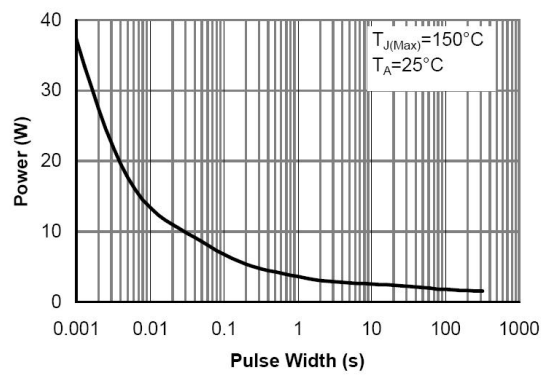
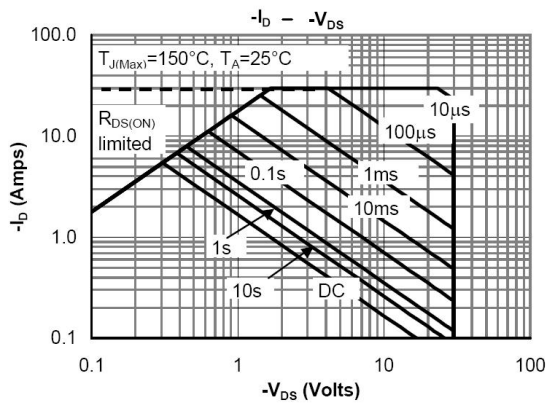
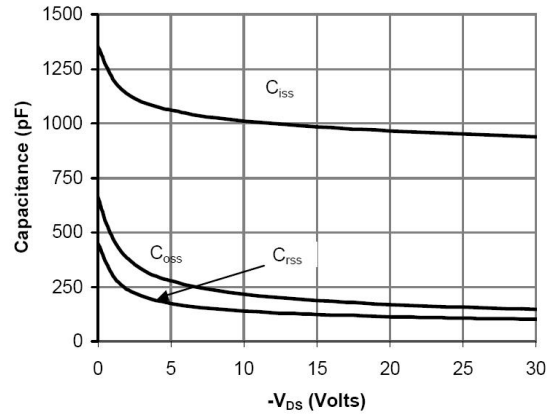
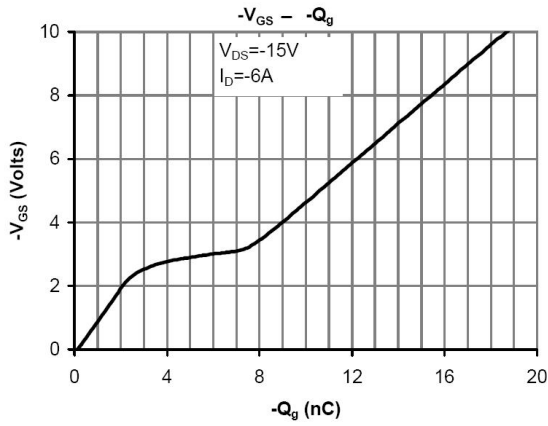
参数 Parameter	符号 Symbol	测试条件 Test Conditions	最小值 Min	典型值 Typ	最大值 Max	单位 Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =-250μA	-30			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =-24V V <sub>GS</sub> =0V			-1.0	μA
		V <sub>DS</sub> =-24V V <sub>GS</sub> =0V T <sub>J</sub> =55°C			-5.0	μA
Gate-Body leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V V <sub>DS</sub> =0V			±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> I <sub>D</sub> =-250μA	-1.2	-2.0	-2.4	V
On state drain current	I <sub>D(on)</sub>	V <sub>DS</sub> =-4.5V V <sub>GS</sub> =-5.0V	30			A
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =-10V I <sub>D</sub> =-6.0A		28	35	mΩ
		V <sub>GS</sub> =-10V I <sub>D</sub> =-6.0A T <sub>J</sub> =125°C		37	45	mΩ
		V <sub>GS</sub> =-4.5V I <sub>D</sub> =-5.0A		44	58	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =-5.0V I <sub>D</sub> =-6.0A		13		S
Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V I <sub>S</sub> =-1.0A		-0.76	-1.0	V
Maximum Body-Diode Continuous Current	I <sub>S</sub>				-4.2	A
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =-15V V <sub>GS</sub> =0V f=1.0MHz		920		pF
Output Capacitance	C <sub>oss</sub>			190		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			122		pF
Gate resistance	R <sub>g</sub>	V <sub>DS</sub> =0V V <sub>GS</sub> =0V f=1.0MHz		3.6		Ω
Total Gate Charge(10V)	Q <sub>g</sub>	V <sub>GS</sub> =-10V V <sub>DS</sub> =-15V I <sub>D</sub> =-6.0A		18.5		nC
Total Gate Charge(4.5V)				9.6		nC
Gate-Source Charge	Q <sub>gs</sub>			2.7		nC
Gate-Drain Charge	Q <sub>gd</sub>			4.5		nC
Turn-On Delay Time	t <sub>d(on)</sub>				7.7	
Turn-On Rise Time	t <sub>r</sub>	V <sub>DS</sub> =-15V V <sub>GS</sub> =-10V R <sub>L</sub> =2.7Ω R <sub>GEN</sub> =3Ω		5.7		ns
Turn-Off Delay Time	t <sub>d(off)</sub>			20.2		ns
Turn-Off Fall Time	t <sub>f</sub>			9.5		ns
Body Diode Reverse Recovery Time	t <sub>rr</sub>		I <sub>F</sub> =-6.0A dI/dt=100A/μs		20	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> =-6.0A dI/dt=100A/μs		8.8		nC

P-沟道电参数曲线图 / P-CHANNEL Electrical Characteristic Curve





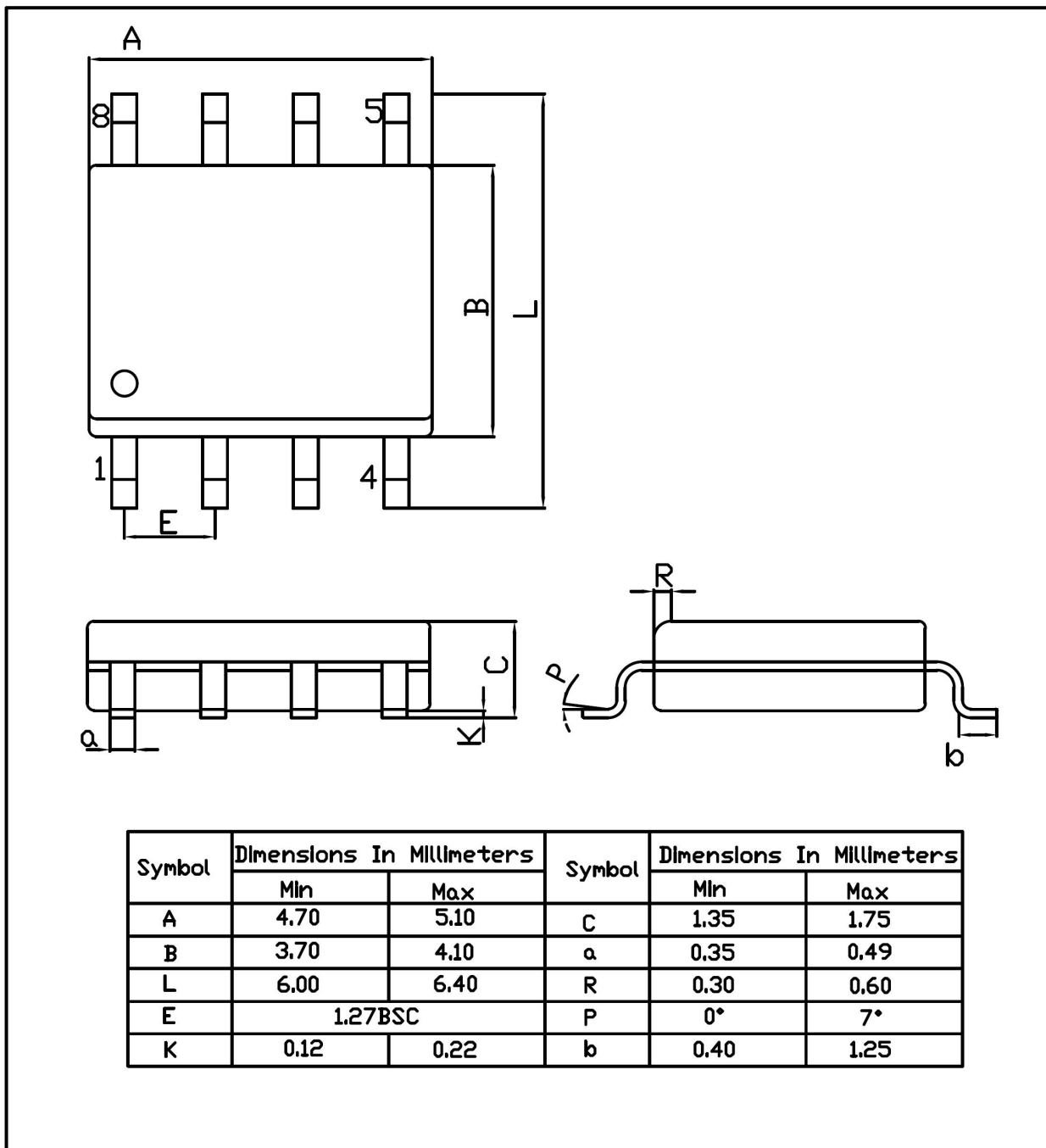
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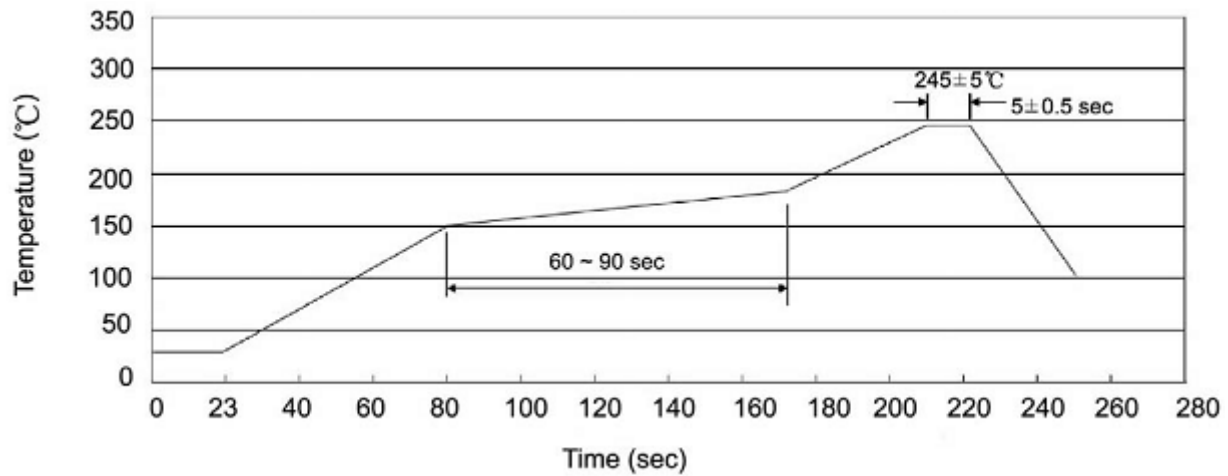
SOP-8

Unit:mm





**回流焊温度曲线图(无铅) / Temperature Profile for IR Reflow Soldering(Pb-Free) 4606**



说明：

- 1、预热温度 25 ~ 150°C，时间 60 ~ 90sec；
- 2、峰值温度 245±5°C，时间持续为 5±0.5sec；
- 3、焊接制程冷却速度为 2 ~ 10°C/sec.

Note:

- 1.Preheating:25~150°C, Time:60~90sec.
- 2.Peak Temp.:245±5°C, Duration:5±0.5sec.
3. Cooling Speed: 2~10°C/sec.

**耐焊接热试验条件 / Resistance to Soldering Heat Test Conditions**

温度：260±5°C

时间：10±1 sec.

Temp.:260±5°C

Time:10±1 sec

**包装规格 / Packaging SPEC.**

卷盘包装 / REEL

Package Type 封装形式	Units 包装数量					Dimension 包装尺寸 (unit: mm <sup>3</sup> )		
	Units/Reel 只/卷盘	Reels/Inner Box 卷盘/盒	Units/Inner Box 只/盒	Inner Boxes/Outer Box 盒/箱	Units/Outer Box 只/箱	Reel	Inner Box 盒	Outer Box 箱
SOP/ESOP-8	4,000	2	8,000	5	40,000	13" ×16	360×360×50	385×257×392